	<b>Title:</b>	Performance report for SiT9366, 200 MHz, LVDS		
	<b>Type:</b>	Performance report	<b>Rev:</b>	1.0
	<b>Orig:</b>		<b>Date:</b>	April 16, 2018

## Performance report for SiT9366 - 200 MHz, LVDS

### Conditions:

- Frequency 200 MHz
- VDD: 2.5 V, 3.3 V
- Room temperature
- Termination:
  - o 100  $\Omega$  between both outputs.

### Equipment:

Model	Measurement / Purpose
Keysight DSA90604A (6 GHz, 20 Gbps)	Period jitter, differential voltage swing, rise/fall time, duty cycle
Keysight 5052B Signal Source Analyzer	Phase noise, integrated phase jitter
Keysight 34980A	Power supply current
Keysight E3631A	Power supply
Keysight 53230A	Frequency

### Test setup:

For waveform parameters measurement (rise/fall time, differential swing, duty cycle), both DUT outputs are terminated with 100  $\Omega$  differential. Output signals are measured using Keysight 1134B active probe with Keysight N5425B probe head. All measurements are applied to the differential waveform. Figure 1 shows test setup diagram for waveform parameters measurement.

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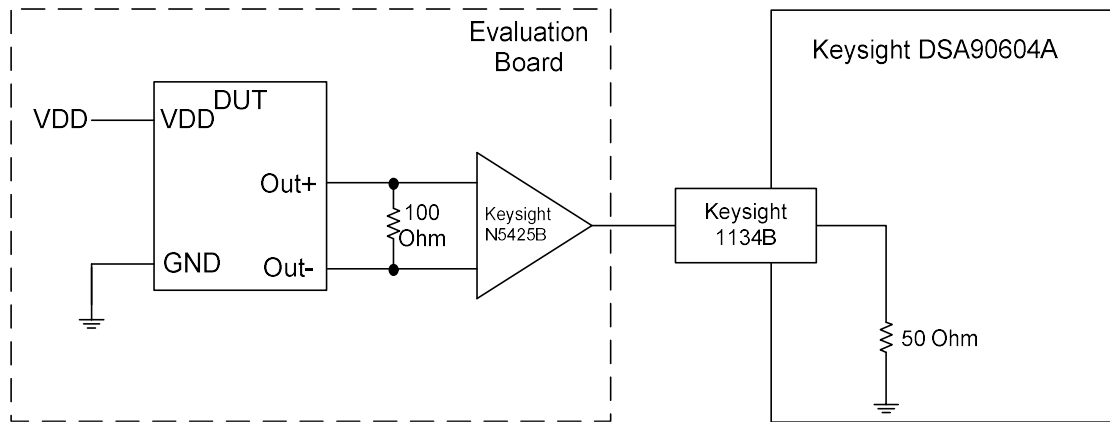


Figure 1: Test setup for measuring waveform parameters (rise/fall time, differential swing, duty cycle)

For period jitter measurement outputs are connected through AC-coupling capacitors to the oscilloscope channels. Signals are subtracted inside the oscilloscope. All measurements applied to differential waveform. Figure 2 shows test setup diagram for period jitter measurement.

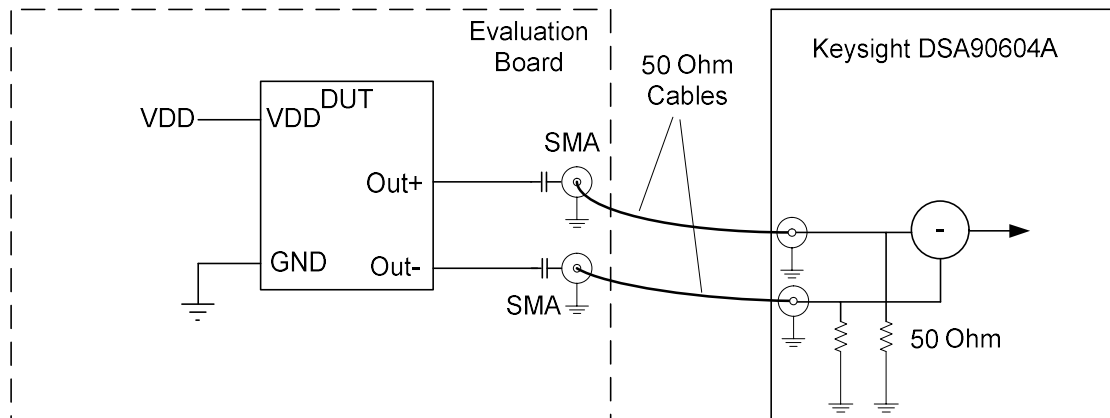


Figure 2: Test setup for measuring period jitter

For phase noise measurements, differential signal is converted to single-ended using impedance matching transformer. Transformer's output is connected to measurement instrument. Figure 3 shows test setup diagram for phase noise measurement.

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Figure 3: Test setup for measuring phase noise.

For IDD measurement device output is floating. For frequency measurement differential-to-single-ended converter is used.

**Data:**

- Phase noise
- Integrated phase jitter
- RMS period jitter
- Peak-to-peak period jitter
- Rise/fall time
- Duty cycle
- Differential output swing
- IDD
- Frequency stability over temperature

Table 1: Summary performance data

Parameter	Units	Voltage	
		2.5 V	3.3 V
Integrated Phase jitter (1.875 MHz - 20 MHz)	fs, rms	89	90
Integrated Phase jitter (12 kHz - 20 MHz)	fs, rms	243	245
Period jitter	ps, rms	0.75	0.77
Period jitter (10,000 cycles)	ps, pk-pk	6.14	5.92
Duty cycle	%	49.9	50.3
Rise time (20% - 80%)	ps	387	389
Fall time (80% - 20%)	ps	385	369
Differential voltage swing	V	0.82	0.81
Current consumption (no load, output enabled)	mA	67.6	68.1
Current consumption (no load, output disabled)	mA	50.2	50.6

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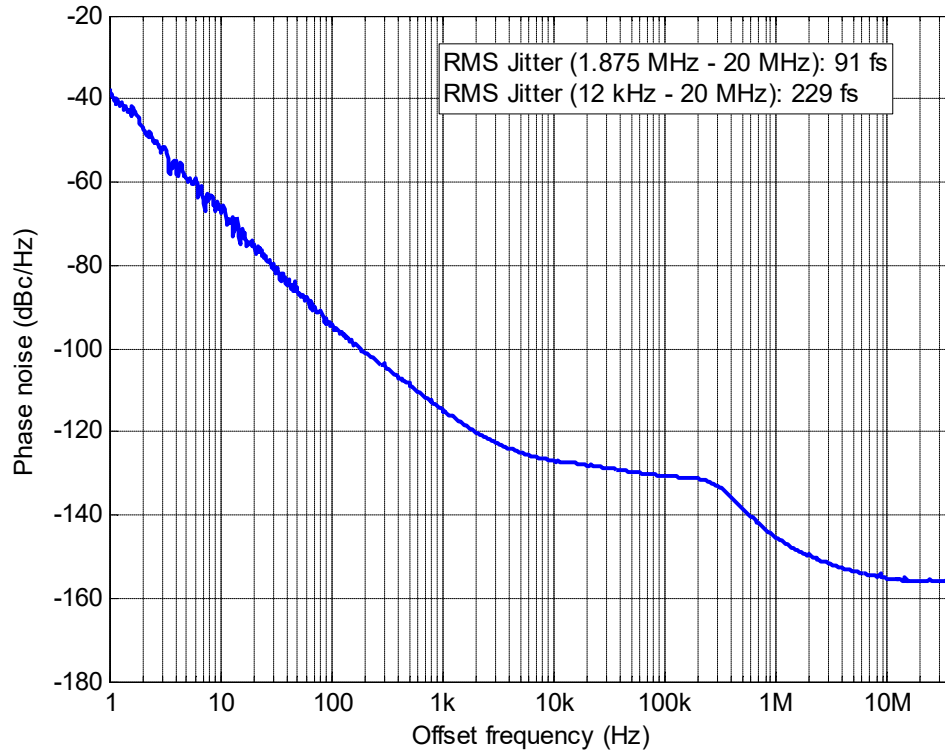


Figure 4: Phase noise, 2.5 V

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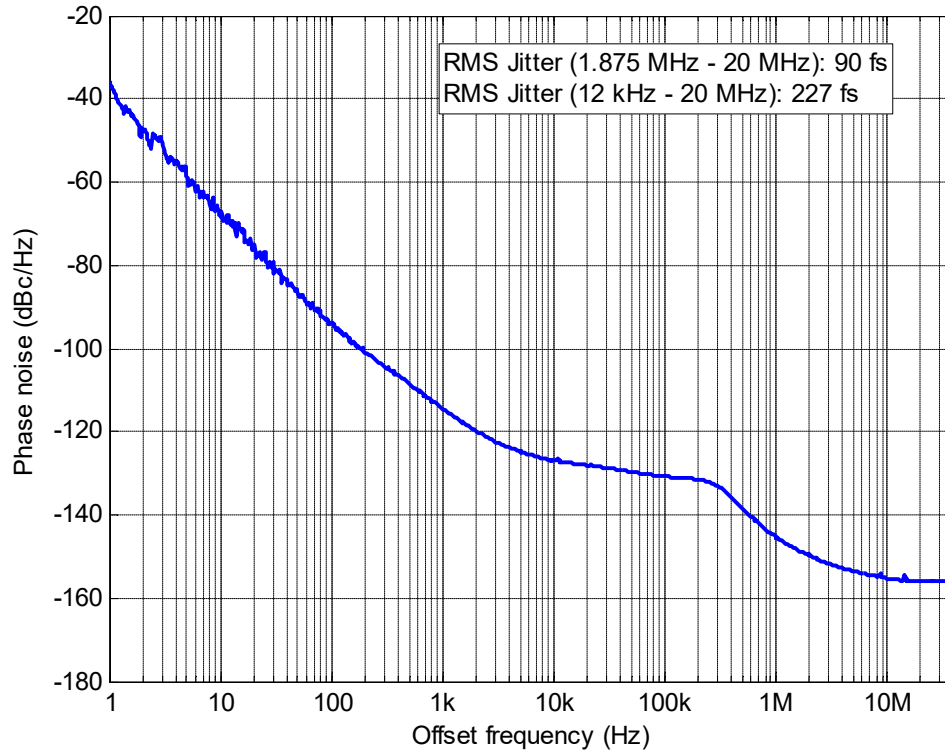



Figure 5: Phase noise, 3.3 V

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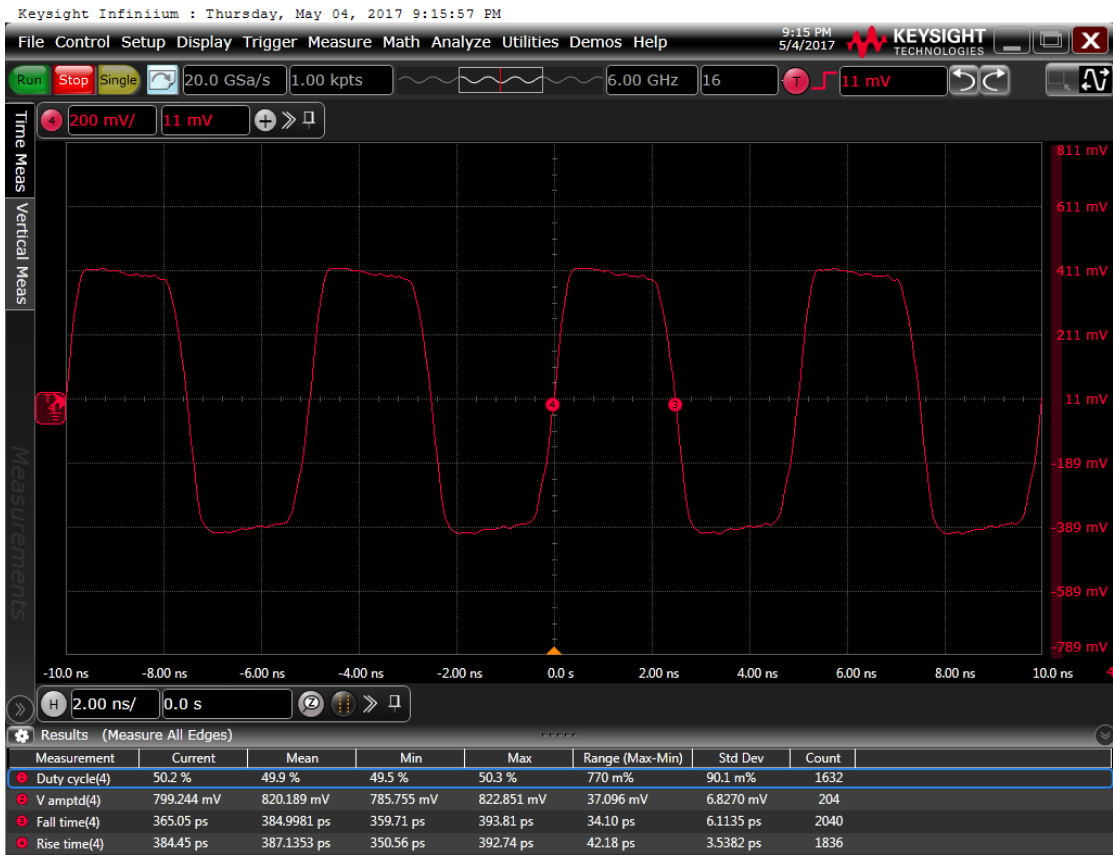


Figure 6: Output waveform, 2.5 V

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Figure 7: Output waveform, 3.3 V

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Figure 8: Frequency stability\* over temperature, 2.5 V

\*SiT9366 frequency stability is independent of output frequency.

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Figure 9: Frequency stability over temperature, 3.3 V

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